

N-Ch 100V Fast Switching MOSFETs

- ★ Super Low Gate Charge
- ★ Green Device Available
- ★ Excellent Cdv/dt effect decline
- ★ Advanced high cell density Trench technology

Product Summary



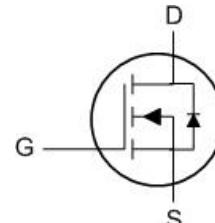
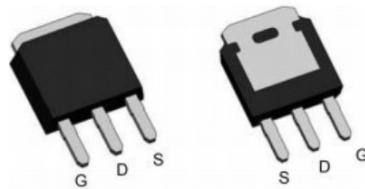
| BVDSS | RDS(ON) | ID |
|-------|---------|-----|
| 100V | 88 mΩ | 15A |

Description

The XR15N10Z is the highest performance trench N-ch MOSFETs with extreme high cell density, which provide excellent RDS(ON) and gate charge for most of the synchronous buck converter applications.

The XR15N10Z meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

TO251 Pin Configuration



Absolute Maximum Ratings

| Symbol | Parameter | Rating | Units |
|---------------------------|--|------------|-------|
| V_{DS} | Drain-Source Voltage | 100 | V |
| V_{GS} | Gate-Source Voltage | ± 20 | V |
| $I_D @ T_c = 25^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 15 | A |
| $I_D @ T_c = 100^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 8 | A |
| $I_D @ T_A = 25^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 3 | A |
| $I_D @ T_A = 70^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 2.4 | A |
| I_{DM} | Pulsed Drain Current ² | 20 | A |
| EAS | Single Pulse Avalanche Energy ³ | 6.1 | mJ |
| I_{AS} | Avalanche Current | 10 | A |
| $P_D @ T_c = 25^\circ C$ | Total Power Dissipation ³ | 30 | W |
| $P_D @ T_A = 25^\circ C$ | Total Power Dissipation ³ | 2 | W |
| T_{STG} | Storage Temperature Range | -55 to 150 | °C |
| T_J | Operating Junction Temperature Range | -55 to 150 | °C |

Thermal Data

| Symbol | Parameter | Typ. | Max. | Unit |
|-----------------|--|------|------|------|
| $R_{\theta JA}$ | Thermal Resistance Junction-ambient ¹ | --- | 62 | °C/W |
| $R_{\theta JC}$ | Thermal Resistance Junction-Case ¹ | --- | 6.6 | °C/W |

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Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise specified)

| Symbol | Parameter | Test Condition | Min. | Typ. | Max. | Units |
|---|--|--|------|------|-----------|------------------|
| Off Characteristics | | | | | | |
| $V_{(\text{BR})\text{DSS}}$ | Drain-Source Breakdown Voltage | $V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$ | 100 | - | - | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS}=100\text{V}$, $V_{GS}=0\text{V}$, | - | - | 1.0 | μA |
| I_{GSS} | Gate to Body Leakage Current | $V_{DS}=0\text{V}$, $V_{GS}=\pm 20\text{V}$ | - | - | ± 100 | nA |
| On Characteristics | | | | | | |
| $V_{GS(\text{th})}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$ | 1.0 | 1.5 | 2.5 | V |
| $R_{DS(\text{on})}$ note3 | Static Drain-Source on-Resistance | $V_{GS}=10\text{V}$, $I_D=5\text{A}$ | - | 88 | 110 | $\text{m}\Omega$ |
| | | $V_{GS}=4.5\text{V}$, $I_D=3\text{A}$ | - | 96 | 140 | $\text{m}\Omega$ |
| Dynamic Characteristics | | | | | | |
| C_{iss} | Input Capacitance | $V_{DS}=25\text{V}$, $V_{GS}=0\text{V}$, $f=1.0\text{MHz}$ | - | 765 | - | pF |
| C_{oss} | Output Capacitance | | - | 38 | - | pF |
| C_{rss} | Reverse Transfer Capacitance | | - | 33 | - | pF |
| Q_g | Total Gate Charge | $V_{DS}=50\text{V}$, $I_D=2\text{A}$, $V_{GS}=10\text{V}$ | - | 18 | - | nC |
| Q_{gs} | Gate-Source Charge | | - | 2.5 | - | nC |
| Q_{gd} | Gate-Drain("Miller") Charge | | - | 4 | - | nC |
| Switching Characteristics | | | | | | |
| $t_{d(on)}$ | Turn-on Delay Time | $V_{DS}=50\text{V}$, $I_D=3\text{A}$, $R_G=1.8\Omega$, $V_{GS}=10\text{V}$ | - | 7.5 | - | ns |
| t_r | Turn-on Rise Time | | - | 6 | - | ns |
| $t_{d(off)}$ | Turn-off Delay Time | | - | 21 | - | ns |
| t_f | Turn-off Fall Time | | - | 9 | - | ns |
| Drain-Source Diode Characteristics and Maximum Ratings | | | | | | |
| I_S | Maximum Continuous Drain to Source Diode Forward Current | - | - | 10 | - | A |
| I_{SM} | Maximum Pulsed Drain to Source Diode Forward Current | - | - | 40 | - | A |
| V_{SD} | Drain to Source Diode Forward Voltage | $V_{GS}=0\text{V}$, $I_S=10\text{A}$ | - | - | 1.2 | V |
| t_{rr} | Body Diode Reverse Recovery Time | $I_F=3\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$ | - | 21 | - | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | | - | 22 | - | nC |

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition : $T_J=25^\circ\text{C}$, $V_{DD}=30\text{V}$, $V_G=10\text{V}$, $L=0.5\text{mH}$, $R_G=25\Omega$, $I_{AS}=4\text{A}$ 3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$

Typical Performance Characteristics

Figure 1: Output Characteristics

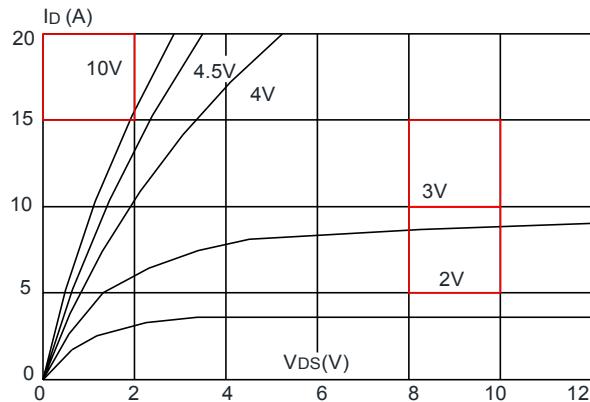


Figure 3: On-resistance vs. Drain Current

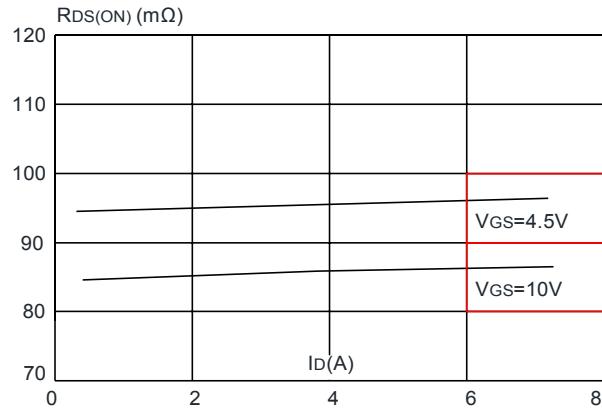


Figure 5: Gate Charge Characteristics

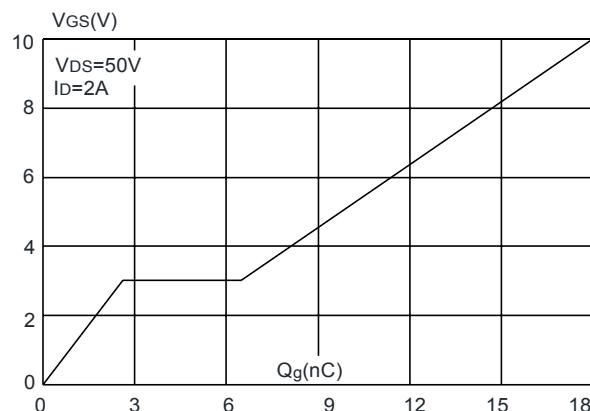


Figure 2: Typical Transfer Characteristics

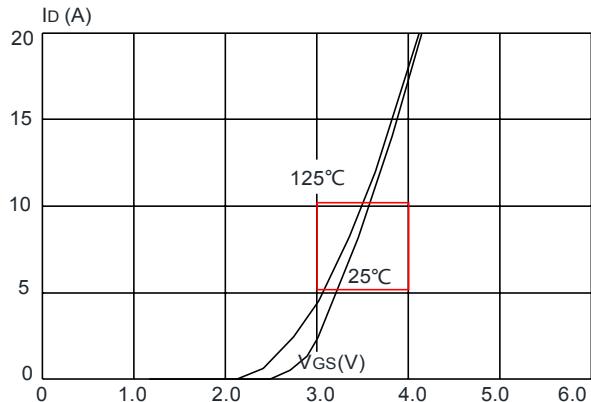


Figure 4 : Body Diode Characteristics

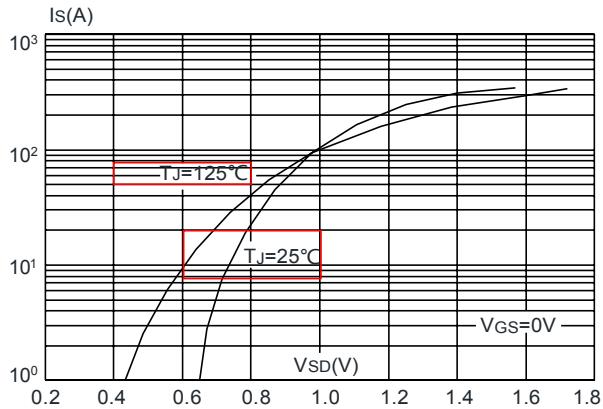
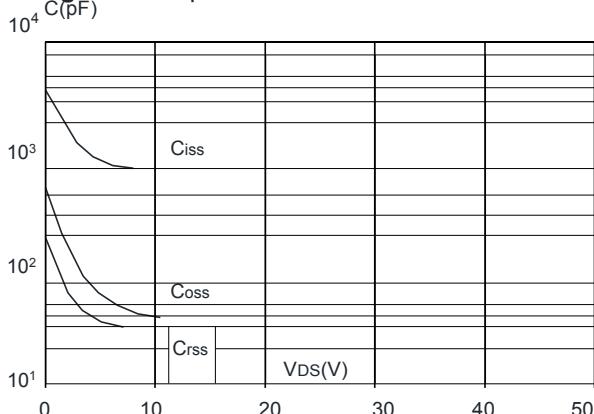


Figure 6: Capacitance Characteristics



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Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

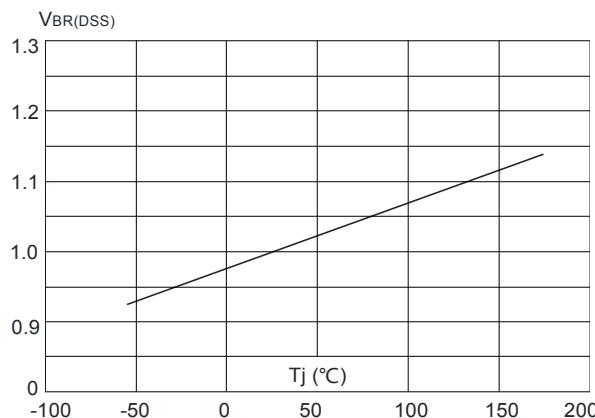


Figure 9: Maximum Safe Operating Area

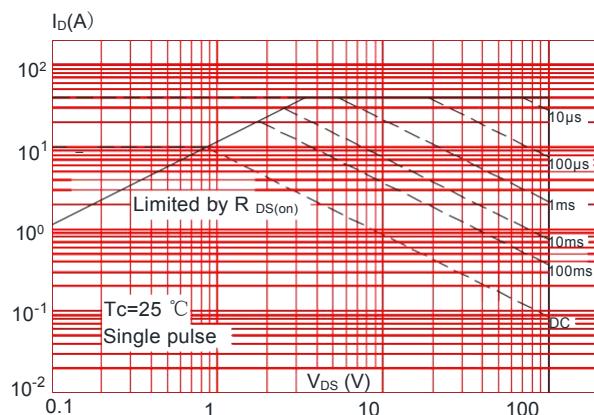


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

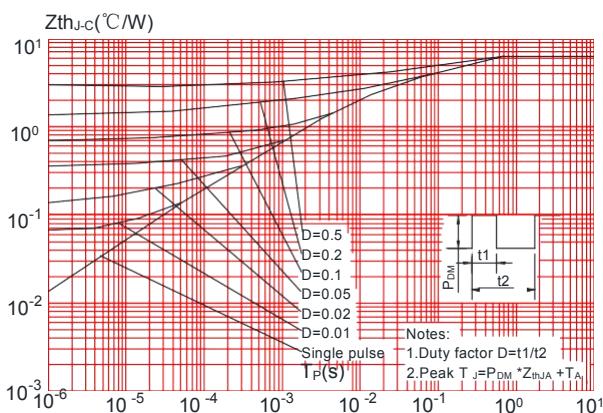


Figure 8: Normalized on Resistance vs. Junction Temperature

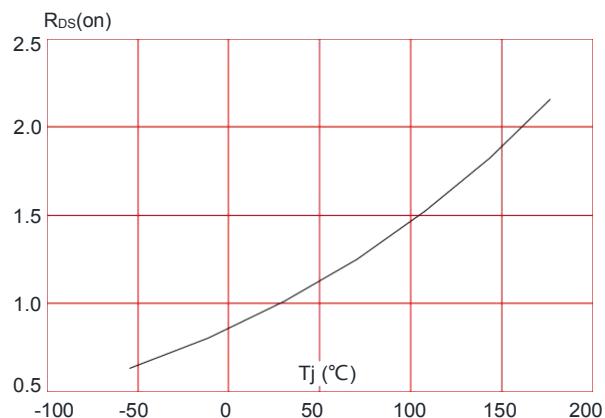
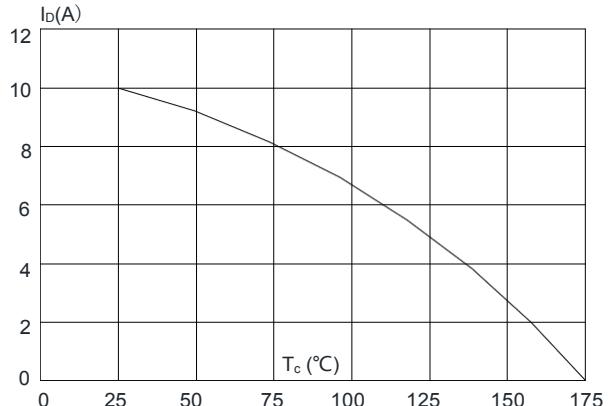


Figure 10: Maximum Continuous Drain Current vs. Case Temperature



Package Mechanical Data TO 251

